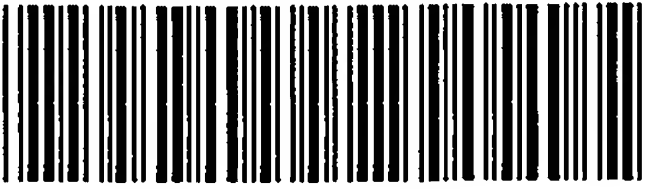


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/617,826	CHEN ET AL.	
	Examiner	Art Unit	
	Leon J. Harper	2166	

SEARCHED			
Class	Subclass	Date	Examiner
707	10,104.1, 100	1/4/2006	LJH

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR